

Notice of References Cited	Application/Control No. 10/586,176		Applicant(s)/Patent Under Reexamination KOHLER ET AL.	
	Examiner FERNANDO N. HIDALGO		Art Unit 2827	Page 1 of 1

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	L	US-			
	M	US-			

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.